

Mini PCI Express Connector

1 Scope:

1.1 Contents

This specification covers the requirements for product performance, test methods and quality assurance provisions of MINI PCI Express Connector. Applicable product description and part numbers are as shown in Appendix 1.

2. Applicable Documents:

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1 TYCO Specifications:

A. 109-5000 Test Specification, General Requirements for Test Methods

B. 501-99107 Test Report

2.2 Commercial Standards and Specifications:

A. MIL-STD-202

B. Mini PCI Express Card Electromechanical Specification Revision 1.0

C. EIA-364



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3.	Requirements
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3.1 Design and Construction:

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2 Materials:

A. Contact:

Copper Alloy

Finish:

Contact area: Gold Flash

Tine area :Gold Flash

Underplate :Nickel Plated

B. Housing:

Thermo plastic UL94V-0

C. Solder Peg:

Copper Alloy, Tin Plated over Ni plate.

D. Latch:

Steel, Tin Plated over Ni plate

3.3 Ratings:

A. Voltage Rating: 50 VAC

B. Current Rating: 0.5 A

C. Temperature Rating −55°C to 85°C

D. Reflow Peak Temperature : 250°C MAX.

3.4 Performance Requirements and Test Descriptions :

The product shall be designed to meet the electrical, mechanical and environmental performance requirements specified in Fig. 1. All tests shall be performed in the room temperature, unless otherwise specified.

Rev. B 2 of 7



3.5 Test Requirements and Procedures Summary

Para.	Test Items	Requirements	Procedures				
3.5.1	Examination of Product	Meets requirements of product	Visual inspection				
		drawing	No physical damage				
	Electrical Requirements						
3.5.2	Termination Resistance	55 m Ω Max. (Initial)	Subject mated contacts assembled in				
	(Low Level)	ΔR =20 m Ω Max. (Final)	housing to closed circuit current of 10 mA				
			Max. at open circuit voltage of 20mV Max.				
			obtain resistance value by dividing the				
			measured reading into two.				
			Fig. 3-1.				
			EIA-364-23				
3.5.3	Dielectric withstanding	No creeping discharge nor	0.3 kVAC for 1 minute.				
	Voltage	flashover shall occur.	Test between adjacent circuits of unmated				
		Current leakage: 0.5 mA Max.	connectors.				
			EIA-364-20				
3.5.4	Insulation Resistance	500M Ω Min.(Initial)	Impressed voltage 500 V DC.				
		500M Ω Min.(Final)	Test between adjacent circuits of unmated				
			connectors.				
			EIA-364-21				
3.5.5	Temperature Rising	30 °C Max. under loaded	Measure temperature rising by energized				
		specified current (0.5 A)	current.				
			EIA-364-70 Test method 2				

Fig.1 (CONT.)

Rev. B 3 of 7



		Mechanical Requirement	S				
Para.	Test Items	Requirements	Procedures				
3.5.6	Vibration	No electrical discontinuity	Subject mated connectors				
	(Random)	greater than 1 μ sec. shall	Vibration Frequency: 10 to 55 Hz				
		occur.	Accelerated Velocity: 30.38m/s ²				
		$\Delta R=20 \text{ m}\Omega$ Max. (Final)	(3.1G), rms.				
		, ,	Vibration Direction: In each of 3 mutually				
			perpendicular planes.				
			Duration: 15 minutes each				
			100 mA applied.				
			Module board should be fixed on the connector mount board or test jig.				
			EIA-364-28 Method VII condition D				
3.5.7	Physical Shock	No electrical discontinuity	Accelerated Velocity: 490 m/s ² (50 G)				
	(Normal test)	greater than 1 μ sec.	Waveform: Half sine				
		shall occur.	Duration: 11 m sec.				
		$\Delta R=20 \text{ m}\Omega$ Max. (Final)	Number of Drops: 3 drops each to normal				
			and reversed directions of X, Y and Z				
			axes, totally 18 drops.				
			EIA-364-27 Condition A				
3.5.8	Connector Mating Force	22.5N (2.3kgf) Max.	Operation Speed: 100 mm/min.				
			Measure the force required to mate				
			connectors (In this test, the force required				
			to turn PCB before it engages on lacking,				
			is excluded).				
			EIA-364-13				
3.5.9	Durability	ΔR =20 m Ω Max. (Final)	Repeated insertion and extraction of P.C.B				
	(Repeated		to and from the connector with the turns to				
	Mating/Unmating)		lock it and then unlock it for 50 cycles.				
			EIA-364-9				
3.5.10	Durability	No physical damage	No. of cycles : 20 cycles				
	(Preconditioning)						
3.5.11	Reseating	No physical damage	No. of cycles : 3 cycles				
3.5.12	Solderability	Wet Solder Coverage:	Solder Temperature : 245 ± 5 °C				
			Immersion Duration : 3 ± 0.5 seconds				
		95 % Min.	Flux : Alpha 100				
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Fig.1 (CONT.)

Rev. B 4 of 7



	Environmental Requirements						
Para.	Test Items	Requirements	Procedures				
3.5.13	Resistance to Refow	No physical damage shall	Test connector on P.C.Board				
	Soldering Heat	occur	Temperature is measured on a soldering				
			pad. Fig.3				
			Pre-Heat150~200°C: 60~180sec.				
			Heat 217 [°] C Min.: 60∼150sec.				
			Heat Peak 260 +0/-5℃				
			The number of reflow : Once				
3.5.14	Thermal Shock	ΔR =20 m Ω Max. (Final)	Mated connector				
			$-55 +0/-3^{\circ}$ C / 30 min., 85 +3/-0 $^{\circ}$ C / 30				
			min.				
			Making this a cycle, repeat 10 cycles.				
			EIA-364-32, Condition A				
3.5.15	Temperature - Humidity	Insulation resistance	Mated connector,				
	Cycling	500 MΩ Min. (final)	25±3~65±3°C, 50±3~80±3% R.H.				
		ΔR =20 m Ω Max. (Final)	24 cycles				
			Cold shock −10°C performed				
			EIA-364-31				
3.5.16	Thermal Cycling	ΔR =20 m Ω Max. (Final)	Mated connector,				
			15±3~85±3°C				
			Ramps: 2°C/min.				
			Dwell time: 5min. Min.				
			10 Cycle				
3.5.17	Temperature Life	$\Delta R = 20 \text{ m}\Omega$ Max. (Final)	Mated connector				
	(Heat Aging)		115°C, Duration: 240 hours				
	, , , , , , , , , , , , , , , , , , , ,		EIA-364-17, Method A				
3.5.18	Temperature Life	No physical damage	Mated connector				
	(Preconditioning)		115°C, Duration: 96 hours				
			EIA-364-17, Method A				
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Fig. 1 (End)

Rev. B 5 of 7



4. Product Qualification Test Sequence

	Test Group										
Test Examination	1	2	3(b)	4(b)	5	6	7	8	9	10	11
rest Examination		Test Sequence (a)									
Examination of Product	1, 5	1, 3	1, 5, 8	1, 4	1, 3	1, 4	1, 3	1, 3	1, 5, 8, 11	1, 5, 8	1, 5, 8, 11
Termination Resistance (Low Level)			2, 6, 9	2, 5		2, 5			2, 6, 9, 12	2, 6, 9	2, 6, 9, 12
Dielectric withstanding Voltage	2, 6										
Insulation Resistance	3, 7										
Temperature rising		2									
Vibration (Random)			7								
Physical Shock				3							
Connector Mating Force					2						
Durability (Repeated mate/unmate)						3					
Durability (Proconditioning)			3						3	3	3
Reseating									10	7	10
Solderability							2				
Resistance to Reflow Soldering Heat								2			
Temperature Humidity Cycling	4								7		
Thermal Shock									4		
Thermal Cycling											7
Temperature Life (Heat Aging)										4	
Temperature Life (Proconditioning)			4	_							4

FIG.2

a) Numbers indicate sequence in which the tests are performed.

b) In these test groups, no electrical discontinuity shall occur.

Rev. B 6 of 7

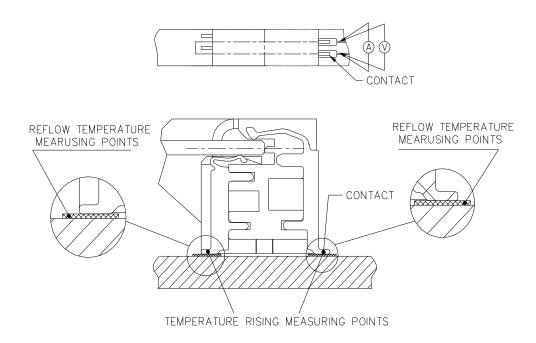


Fig. 3-1 Termination Resistance Measuring points, Temperature Rising Measuring points, and Reflow Temperature Measuring points.

Product Part No.	Description		
1759503-1	0.8MM PITCH MINI PCI EXPRESS CONNECTOR ASSEMBLY (8MM HEIGHT)		
1759513-1	0.8MM PITCH MINI PCI EXPRESS CONNECTOR ASSEMBLY (9MM HEIGHT)		
1759516-1	0.8MM PITCH MINI PCI EXPRESS CONNECTOR ASSEMBLY (10.5MM HEIGHT)		
1759546-1	0.8MM PITCH MINI PCI EXPRESS CONNECTOR ASSEMBLY (9.9MM HEIGHT)		

Appendix.1

Rev. B 7 of 7